



7/19/2012

**RELIABILITY MONITOR REPORT
FOR**

MFN 1.2 μ m CBiCMOS (HV3)

MAXIM Integrated Products

**120 San Gabriel Dr.
Sunnyvale, CA 94086**

**This Report was prepared by
Maxim Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX9950DCCB

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 29842 QUANTITY: 154 FAILS: 0 FITS: 3.8

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 7/1/2011 and 6/30/2012 .

Process Information:

Process Description: MFN 1.2µm CBiCMOS (HV3)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1046	MAX9950DCCB+	135C	1000 HRS	77	0	NGM0CA018Q1
HIGH TEMP OP LIFE	1046	MAX9950DCCB+	135C	1000 HRS	77	0	NGM0CA018Q2
Total:						0	

FAILURE RATE: MTTF (YRS): 29842 QUANTITY: 154 FAILS: 0 FITS: 3.8